

PIN-CONTROLLED 1–711 MHZ JITTER CLEANING CLOCK

Features

- **Provides jitter attenuation for any clock** \blacksquare frequency
- One clock input / two clock outputs
- Input/output frequency range: 1–711 MHz
- Ultra low iitter: 300 fs (12 kHz–20 MHz) typical
- Simple pin control interface
- Selectable loop bandwidth for jitter attenuation: 60 Hz–8.4 kHz
- Meets OC-192 GR-253-CORE jitter specifications

Applications

- Data converter clocking
- Wireless infrastructure
- Networking, SONET/SDH
- **Description**

 Selectable output clock signal format: LVPECL, LVDS, CML or CMOS

- Single supply: 1.8 , 2.5 , or 3.3 V
- Loss of lock and loss of signal alarms
- **VCO** freeze during LOS/LOL
- On-chip voltage regulator with high PSRR
- Small size: 6 x 6 mm, 36-QFN
- Wide temperature range: –40 to +85 ºC
- Switches and routers
- Medical instrumentation
- Test and measurement
- The Si5317 is a flexible 1:1 jitter cleaning clock for high-performance applications that require jitter attenuation without clock multiplication. The Si5317 accepts a single clock input ranging from 1 to 711 MHz and generates two low jitter clock outputs at the same frequency. The clock frequency range and loop bandwidth are selectable from a simple look-up table. The Si5317 is based on Silicon Laboratories' 3rd-generation DSPLL $^{\circledR}$ technology, which provides jitter attenuation on any frequency in a highly integrated PLL solution that eliminates the need for external VCXO and loop filter components. The DSPLL loop bandwidth is user selectable, providing jitter performance optimization at the application level.

Functional Block Diagram

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(V_{DD} = 1.8 ±5%, 2.5 ±10%, or 3.3 V ±10%, T_A = -40 to 85 °C)

Table 2. DC Characteristics

(V_{DD} = 1.8 ±5%, 2.5 ±10%, or 3.3 V ±10%, T_A = -40 to 85 °C)

Notes:

1. LVPECL outputs require VDD \geq 2.25 V.

2. This is the amount of leakage that the 3L inputs can tolerate from an external driver. See [Figure 3 on page 9.](#page-8-2) In most designs, an external resistor voltage divider is recommended.

Table 2. DC Characteristics (Continued)

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Figure 2. Rise/Fall Time Characteristics

1.1. Three-Level (3L) Input Pins (No External Resistors)

Figure 3. Three-Level Input Pins

1.2. Three-Level Input Pins (Example with External Resistors)

One of eight resistors from a Panasonic EXB-D10C183J (or similar) resistor pack

Figure 4. Three-Level Input Pins

Table 3. Three-Level Input Pins1,2,3,4

Notes:

- **1.** The current parameters are the amount of leakage that the 3L inputs can tolerate from an external driver using the external resistor values indicated in this example. In most designs, an external resistor voltage divider is recommended.
- **2.** Resistor packs are only needed if the leakage current of the external driver exceeds the current specified in [Table 2](#page-3-3), Iimm. Any resistor pack may be used (e.g. Panasonic EXB-D10C183J). PCB layout is not critical.
- **3.** If a pin is tied to ground or V_{DD}, no resistors are needed.
- **4.** If a pin is left open (no connect), no resistors are needed.

Table 4. AC Characteristics

(V_{DD} = 1.8 ±5%, 2.5 ±10%, or 3.3 V ±10%, T_A = -40 to 85 °C)

Table 4. AC Characteristics (Continued)

(V_{DD} = 1.8 ±5%, 2.5 ±10%, or 3.3 V ±10%, T_A = –40 to 85 °C)

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(V_{DD} = 1.8 ±5%, 2.5 ±10%, or 3.3 V ±10%, T_A = –40 to 85 °C)

Notes:

1. BWSEL [1:0] loop bandwidth settings provided in [Table 9 on page 22.](#page-21-1)

2. 114.285 MHz 3rd OT crystal used as XA/XB input.

3. $V_{DD} = 2.5 V$

4. $T_A = 85 \text{ °C}$

5. Test condition: f_{IN} = 622.08 MHz, f_{OUT} = 622.08 MHz, LVPECL clock input: 1.19 Vppd with 0.5 ns rise/fall time (20-80%), LVPECL clock output.

Table 6. Thermal Characteristics

(V_{DD} = 1.8 ±5%, 2.5 ±10%, or 3.3 V ±10%, T_A = -40 to 85 °C)

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2. Functional Description

Figure 5. Detailed Block Diagram

2.1. Overview

The Si5317 is a 1:1 jitter-attenuating precision clock for applications requiring sub 1 ps jitter performance. The Si5317 accepts one clock input ranging from 1 to 711 MHz and generates two clock outputs at the same frequency ranging from 1 to 711 MHz. The Si5317 is based on Silicon Laboratories' 3rd-generation DSPLL® technology, which provides jitter attenuation on any frequency in a highly integrated PLL solution that eliminates the need for external VCXO and loop filter components. The nominal operating frequency is selectable from a look-up table. The Si5317 PLL loop bandwidth (BW) is selectable via the BWSEL[1:0] pins and supports a range from 60 Hz to 8.4 kHz.

The Si5317 monitors the input clock for loss-of-signal (LOS) and provides a LOS alarm when it detects missing pulses on the input clock. The device monitors the lock status of the DSPLL. The lock detect algorithm works by continuously monitoring the phase of the input clock in relation to the phase of the feedback clock.

The Si5317 provides a VCO freeze capability that allows the device to continue generation of a stable output clock when the selected input clock is lost. During VCO freeze, the DSPLL latches its VCO settings and uses its XA/XB clock as its frequency reference.

The Si5317 has two output clock drivers and can be configured as four single-ended or two differential outputs. The signal format of the clock output is selectable to support LVPECL, LVDS, CML, or CMOS loads. The device operates from a single 1.8, 2.5, or 3.3 V supply. The use of LVPECL requires a VDD \geq 2.25 V.

3. Frequency Plan Tables

For ease of use, the Si5317 is pin-controlled to enable simple device configuration of the frequency range plan and PLL loop bandwidth via a predefined look-up table. The DSPLL has been optimized for jitter performance and tunability for each frequency range and PLL loop bandwidth provided in [Table 9 on page 22.](#page-21-1)

Many of the control inputs are three levels: High, Low, and Medium. High and Low are standard voltage levels determined by the supply pins: V_{DD} and Ground. If the input pin is left floating, it is driven to nominally half of V_{DD} . Effectively, this creates three logic levels for these controls. See section [6. "Power Supply Filtering" on page 33](#page-32-0) and section [1.2. "Three-Level Input Pins \(Example with External Resistors\)" on page 9](#page-8-1) for additional information.

3.1. Frequency Range Plan

The input to output clock frequency range is set by the 3-level FRQSEL[3:0] and FRQTBL pins. The CKIN and CKOUT is the same frequency range as specified in [Table 8](#page-15-0). Due to the wide tunability of the Si5317, each frequency plan provides overlap between adjacent settings. To select a frequency plan, the desired frequency should be selected as close to the defined center frequency. In certain cases where the desired frequency is exactly between two overlapping plans, either FRQTBL and FRQSEL setting can be used.

3.1.1. PLL Loop Bandwidth Plan

The Si5317's loop bandwidth ranges from 60 Hz to 8.4 kHz. For each frequency range, the corresponding loop bandwidth is provided in a simple look-up table (see [Table 9 on page 22\)](#page-21-1). The loop bandwidth is digitally programmable using the three-level BWSEL [1:0] input pins.

3.2. Output Skew Adjustment

The overall device skew (CKIN to CKOUTn phase delay) is adjustable via the INC and DEC input pins. A positive edge triggered pulse applied to the INC pin increases the device skew defined by [Table 8,](#page-15-0) INC/DEC step size, for each given frequency plan. The identical operation on the DEC pin decreases the skew by the same amount. Using the INC and DEC pins, there is no limit to the range of skew adjustment that can be made. Following a powerup or reset, the overall device skew will revert to the reset value, although the input-to-output skew is effectively random. The rate of change for each INC/DEC operation is defined by the selected loop bandwidth, BWSEL[1:0].

			Frequency Range (MHz)			BWSEL [1:0] (BW in Hz)					INC/DEC Phase	
											Change	
Plan No	FRQTBL	FRQSEL [3:0]	Min	Center	Max	LH	ML	MM	MH	HL	HM	(ns)
$\mathbf 0$	L	LLLL	.95	1.00	1.05		3814	927	230	114	57	0.21
$\mathbf{1}$	L	LLLM	1.00	1.05	1.10	$\overline{}$	3814	927	230	114	57	0.21
$\overline{2}$	L	LLLH	1.05	1.10	1.15	$\overline{}$	3834	931	231	115	57	0.21
3	L	LLML	1.10	1.15	1.20	$\overline{}$	4052	983	244	121	60	0.21
4	L	LLMM	1.15	1.20	1.25	$\overline{}$	4251	1030	255	127	63	0.21
5	L	LLMH	1.20	1.25	1.30	$\overline{}$	4451	1078	267	133	66	0.21
6	L	LLHL	1.25	1.30	1.35	$\overline{}$	4652	1125	279	139	69	0.21
$\overline{7}$	L	LLHM	1.30	1.35	1.40	$\overline{}$	4852	1172	290	145	72	0.21
8	L	LLHH	1.35	1.40	1.45	—	5054	1219	302	150	75	0.21
$\boldsymbol{9}$	L	LMLL	1.40	1.45	1.50	$\overline{}$	5256	1267	314	156	78	0.21
10	L	LMLM	1.45	1.50	1.55	$\overline{}$	5256	1267	314	156	78	0.21
11	L	LMLH	1.50	1.55	1.60	—	5459	1314	325	162	81	0.21
12	L	LMML	1.55	1.60	1.65	$\overline{}$	5866	1409	349	174	87	0.21
13	L	LMMM	1.60	1.65	1.70	$\overline{}$	5866	1409	349	174	87	0.21
14	L	LMMH	1.65	1.70	1.75	$\overline{}$	6071	1457	360	180	89	0.21
15	L	LMHL	1.70	1.75	1.80	$\overline{}$	6276	1504	372	185	92	0.21
16	L	LMHM	1.75	1.80	1.85	$\overline{}$	6483	1552	384	191	95	0.21
17	L	LMHH	1.80	1.85	1.90	$\overline{}$	6688	1599	395	197	98	0.21
18	L	LHLL	1.85	1.90	1.95	$\overline{}$	6895	1647	407	203	101	0.21
19	L	LHLM	1.90	1.95	2.00	4696	2285	560	139	69		0.21
20	L	LHLH	1.95	2.00	2.10	4832	2350	575	143	71	$\overline{}$	0.21
21	L	LHML	2.00	2.10	2.20	4967	2415	591	147	73		0.21
22	L	LHMM	2.10	2.20	2.30	5239	2544	622	154	77		0.21
23	L	LHMH	2.20	2.30	2.40		4052	983	244	121	60	0.21
24	L	LHHL	2.30	2.40	2.50		4251	1030	255	127	63	0.21
25	L	LHHM	2.40	2.50	2.60	$\overline{}$	4451	1078	267	133	66	0.21
26	L	LHHH	2.50	2.60	2.70	$\overline{}$	4651	1125	279	139	69	0.21
27	L	MLLL	2.60	2.70	2.80		4852	1172	290	145	72	0.20
28	L	MLLM	2.70	2.80	2.90	$\overline{}$	5054	1219	302	150	75	0.21
29	L	MLLH	2.80	2.90	3.00	$\overline{}$	5255	1267	314	156	78	0.20
30	L	MLML	2.90	3.00	3.10	—	5458	1314	325	162	81	0.20
31	L	MLMM	3.00	3.10	3.20		5859	1409	349	174	87	0.20
32	L	MLMH	3.10	3.20	3.30	$\overline{}$	5859	1409	349	174	87	0.20
Note: For BWSEL[1:0] settings LL, LM, HH are reserved.												

Table 8. Look-up Tables for Fin = Fout Frequency Range and Loop Bandwidth Settings

3.3. PLL Self-Calibration

An internal self-calibration (ICAL) is performed before operation to optimize loop parameters and jitter performance. While the self-calibration is being performed, the DSPLL is being internally controlled by the selfcalibration state machine. The LOL alarm will be active during ICAL. The self-calibration time t_1 _{OCKHW} is given in [Table 4, "AC Characteristics"](#page-10-0).

Any of the following events will trigger a self-calibration:

- **Power-on-reset (POR)**
- Release of the external reset pin $\overline{\text{RST}}$ (transition of $\overline{\text{RST}}$ from 0 to 1)
- Change in FRQSEL, FRQTBL, BWSEL, or RATE[1:0] pins
- Internal DSPLL registers out-of-range, indicating the need to relock the DSPLL

In any of the above cases, an ICAL will be initiated if a valid input clock exists with no input alarm. The external crystal or reference clock must also be present for the self-calibration to begin. If no valid input clock is present, the self-calibration state machine will wait until it appears, at which time the calibration will start.

After a successful ICAL has been performed with a valid input clock, no subsequent self-calibrations are performed unless one of the above conditions are met. If the input clock is lost following self-calibration, the device enters VCO freeze mode. When the input clock returns, the device relocks to the input clock without performing a selfcalibration.

3.3.1. Input Clock Stability during Internal Self-Calibration

An exit from reset must occur when the selected CKIN clock is stable in frequency with a frequency value that is within the device operating range.

3.3.2. Self-Calibration caused by Changes in Input Frequency

If the selected CKIN frequency varies by 500 ppm or more within the frequency range defined by FRQSEL and FRQTBL since the last calibration, the device may initiate a self-calibration.

3.3.3. Device Reset

Upon powerup, the device internally executes a power-on-reset (POR) which resets the internal device logic. The pin RST can also be used to initiate a reset. The device stays in this state until a valid CKINn is present, when it then performs a PLL self-calibration (refer to section [3.3. "PLL Self-Calibration"](#page-21-0)).

3.3.4. Recommended Reset Guidelines

Follow the recommended RESET guidelines in [Table 9](#page-21-1) that describe when reset should be applied to a device.

Table 9. Si5317 Pins and Reset

3.4. Alarms

Summary alarms are available to indicate the overall status of the input signals. Alarm outputs stay high until all the alarm conditions for that alarm output are cleared.

3.4.1. Loss-of-Signal

The device has loss-of-signal circuitry that continuously monitors CKIN for missing pulses.

An LOS condition on CKIN causes the LOS alarm to become active. Once a LOS alarm is asserted, it remains asserted until the input clock is validated over a designated time period. The time to clear LOS after a valid input clock appears is listed in [Table 4, "AC Characteristics"](#page-10-0). If another error condition on the same input clock is detected during the validation time, then the alarm remains asserted and the validation time starts over.

3.4.1.1. LOS Algorithm

The LOS circuitry divides down each input clock to produce an 8 kHz to 2 MHz signal. The LOS circuitry oversamples this divided down input clock using a 40 MHz clock to search for extended periods of time without input clock transitions. If the LOS monitor detects twice the normal number of samples without a clock edge, a LOS alarm is declared. [Table 4, "AC Characteristics"](#page-10-0) gives the minimum and maximum amount of time for the LOS monitor to trigger.

3.4.1.2. Lock Detect

The PLL lock detection algorithm indicates the lock status on the LOL output pin. The algorithm works by continuously monitoring the phase of the input clock in relation to the phase of the feedback clock. If the time between two consecutive phase cycle slips is greater than the retrigger time, the PLL is in lock. The LOL output has a guaranteed minimum pulse width as shown in [Table 4, "AC Characteristics"](#page-10-0). The LOL pin is also held in the active state during an internal PLL calibration. The retrigger time is automatically set based on the PLL closed loop bandwidth (see [Table 10\)](#page-22-2).

Table 10. Lock Detect Retrigger Time

3.5. VCO Freeze

The Si5317 device features a VCO freeze mode whereby the DSPLL is locked to a frequency value.

If an LOS condition exists on the selected input clock, the device freezes the VCO. In this mode, the device provides a stable output frequency until the input clock returns and is validated. When the device enters VCO freeze, the internal oscillator is initially held to its last frequency value.

3.5.1. Recovery from VCO Freeze

When the input clock signal returns, the device transitions from VCO freeze to the selected input clock.

3.6. PLL Bypass Mode

The Si5317 supports a PLL bypass mode in which the selected input clock is fed directly to both enabled output buffers, bypassing the DSPLL. Internally, the bypass path is implemented with high-speed signaling; however, this path is not a low jitter path and will result in significantly higher jitter on CKOUT. In PLL bypass mode, the input and output clocks will be at the same frequency. PLL bypass mode is useful as a debug tool. The DSBL2_BY pin is used to select the PLL Bypass Mode according to [Table 11](#page-23-1). Bypass mode is not supported for CMOS clock outputs.

DSBL2/BYPASS	Function				
	CKOUT2 Enabled				
м	CKOUT2 Disabled				
	PLL Bypass Mode w/ CKOUT2 Enabled				

Table 11. DSBL2/BYPASS Pin Settings

Figure 6. Bypass Signal

4. High-Speed I/O

4.1. Input Clock Buffer

The Si5317 provides differential inputs for the CKIN clock input. This input is internally biased to a common mode voltage (see [Table 2, "DC Characteristics"](#page-3-3)) and can be driven by either a single-ended or differential source. No additional external bias is required. [Figure 7](#page-24-2) through [Figure 10](#page-25-0) show typical interface circuits for LVPECL, CML, LVDS, or CMOS input clocks. Note that the jitter generation improves for higher levels on CKINn within the limits in [Table 4, "AC Characteristics"](#page-10-0).

AC coupling the input clocks is recommended because it removes any issue with common mode input voltages. DC coupling is acceptable if the device driving the Si5317 meets all of the input clock requirements, including the input common mode range and the peak-to-peak swing specifications. [Figure 7](#page-24-2) and [Figure 8](#page-24-3) shows various examples of different input termination arrangements. Unused inputs can be left unconnected.

Figure 7. Differential LVPECL Termination

Figure 8. Single-ended LVPECL Termination

Additional Notes:

1. Attenuation circuit limits overshoot and undershoot.

2. Not to be used with non-square wave input clocks.

Figure 10. CMOS Termination with Attenuation and AC-Coupling (1.8, 2.5, 3.3 V)

4.2. Output Clock Driver

The Si5317 has a flexible output driver structure that can drive a variety of loads, including LVPECL, LVDS, CML, and CMOS formats. The signal format is selected for CKOUT output using the SFOUT [1:0] pins. This modifies the output common mode and differential signal swing. See [Table 2, "DC Characteristics"](#page-3-3) for output driver specifications. The SFOUT [1:0] pins are three-level input pins with the states designated as L (ground), M ($V_{DD}/2$), and H (V_{DD}). [Table 12](#page-26-1) shows the signal formats based on the supply voltage and the type of load being driven. When SFOUT = LH for CMOS, bypass mode is not supported.

SFOUT[1:0]	Signal Format				
HL.	CML				
нм	LVDS				
LH	CMOS				
l M	Disabled				
ΜН	LVPECL				
ML	Low-swing LVDS				
All Others	Reserved				

Table 12. Output Signal Format Selection (SFOUT)

Figure 11. Typical Differential Output Circuit

Figure 12. Typical CMOS Output Circuit (Tie CKOUTn+ and CKOUTn– Together)

For the CMOS setting (SFOUT = LH), both output pins drive single-ended in-phase signals and should be externally shorted together to obtain the drive strength specified in [Table 2, "DC Characteristics".](#page-3-3)

Figure 13. Disable CKOUT Structure

The SFOUT [1:0] pins can also be used to disable both outputs. Disabling the output puts the CKOUT+ and CKOUT– pins in a high-impedance state relative to V_{DD} (common mode tri-state) while the two outputs remain connected to each other through a 200 Ω on-chip resistance (differential impedance of 200 Ω). The maximum amount of internal circuitry is powered down, minimizing power consumption and noise generation (see [Figure 13\)](#page-27-0). Recovery from the disable mode requires additional time as specified in [Table 4, "AC Characteristics"](#page-10-0).

5. Crystal/Reference Clock Input

The device can use an external crystal or external clock as a reference. If an external clock is used, it must be ac coupled. With appropriate buffers, the same external reference clock can be applied to CKIN. Although the reference clock input can be driven single ended (See [Figure 14\)](#page-28-1), the best performance is with a crystal or differential clock source.

For 2.5 V operation, change 130 Ω to 82 Ω .

Figure 15. Sinewave External Reference Clock Input Example

Figure 16. Differential External Reference Clock Input Example

5.1. Crystal/Reference Clock Selection

An external low-jitter clock or a low-cost crystal is used as part of a fixed-frequency oscillator within the DSPLL. This external clock is required for the device to perform jitter attenuation. Silicon Laboratories recommends using a high-quality crystal.

In VCO freeze, the DSPLL remains locked to this external clock. Any changes in the frequency of this clock when the DSPLL is in VCO freeze will be tracked by the output of the device. Note that crystals can have temperature sensitivities. See "AN591: Crystal Selection for the Si5315 and Si5317" for a list of approved crystals for the Si5317 and guidance in their selection. AN591 can be downloaded from the Silicon Labs web site: www.silabs.com.

RATE[1:0]	Type	Recommended	Lower limit	Upper limit		
HH	Reserved					
HM	Reserved					
HL	Reserved					
MH	External clock	114.285 MHz	109 MHz	125.5 MHz		
MM	3rd overtone crystal*	114.285 MHz				
ML	Reserved					
LH	Reserved					
LM	External clock	38.88 MHz	37 MHz	41 MHz		
LL	Fundamental mode crystal*					
*Note: See "AN591: Crystal Selection for the Si5315 and Si5317."						

Table 13. XA/XB Reference Sources and Frequencies

Because the crystal is used as a jitter reference, rapid changes of the crystal temperature can temporarily disturb the output phase and frequency. For example, it is recommended that the crystal not be placed close to a fan that is being turned off and on. If a situation such as this is unavoidable, the crystal should be thermally isolated with an insulating cover.

5.1.1. XA/XB Clock Drift

During VCO freeze, long-term and temperature-related drift of the XA/XB clock input results in a one-to-one drift of the output frequency. The stability of the any frequency output is identical to the drift of the XA/XB frequency. This means that for the most demanding applications where the drift of a crystal is not acceptable, an external temperature-compensated or ovenized oscillator will be required. Drift is not an issue unless the part is in VCO freeze. Also, the initial accuracy of the XA/XB oscillator (or crystal) is not relevant.

5.1.2. XA/XB Jitter

Jitter on the XA/XB input has a roughly one-to-one transfer function to the output jitter over the bandwidth ranging from 100 Hz up to 30 kHz. If a crystal is used on the XA/XB pins, this will have low jitter if a suitable crystal is in use. If the XA/XB pins are connected to an external oscillator, the jitter of the external oscillator may contribute significantly to the output jitter.

5.1.3. Jitter Attenuation Performance

The internal VCO uses the XA/XB clock on the XA/XB pins as its reference for jitter attenuation. The XA/XB pins support either a crystal input or an input buffer single-ended or differential clock input, such that an external oscillator can become the reference source. In either case, the device accepts a wide margin in absolute frequency of the XA/XB input (refer to section [3.5.1. "Recovery from VCO Freeze" on page 23\)](#page-22-3). In VCO freeze, the Si5317's output clock stability matches the clock supplied on the XA/XB pins. The external crystal or clock must be selected based on the stability requirements of the application if VCO freeze is a key requirement. However, care must be exercised in certain areas for optimum performance. For examples of connections to the XA/XB pins, refer to section 5. [Figure 22, "Si5317 Typical Application Circuit," on page 35.](#page-34-1)

Figure 17. Typical XA-XB Jitter Transfer Function

5.1.4. Reference Clock Frequency

Based on the application and desired output frequency, care should be exercised in selecting the frequency on the reference used for XA/XB. When the CKOUT operating frequency is close to having a simple integer relationship, significant spurs can occur. For example, compare the spurs when the CKOUT operating frequency is 622.08 MHz with a reference of 114.285 MHz (see [Figure 21\)](#page-33-2) versus a reference frequency of 38.88 MHz, which is 16 times the XA/XB reference (see [Figure 18\)](#page-31-0).

Figure 18. Effect of Reference Frequency on Spurs

6. Power Supply Filtering

This device incorporates an on-chip voltage regulator to power the device from supply voltages of 1.8, 2.5, or 3.3 V. Internal core circuitry is driven from the output of this regulator while I/O circuitry uses the external supply voltage directly. [Table 4, "AC Characteristics"](#page-10-0) gives the sensitivity of the on-chip oscillator to changes in the supply voltage. The center ground pad under the device must be electrically and thermally connected to the ground plane. See [Figure 25, "Ground Pad Recommended Layout," on page 42](#page-41-1).

Figure 19. Typical Power Supply Bypass Network

Power Supply Noise to Output Transfer Function

Frequency of Power Supply Noise (kHz)

7. Typical Phase Noise Plots

The following is a typical phase noise plot. The clock input source was a Rohde and Schwarz model SML03 RF Generator. The phase noise analyzer was an Agilent model E5052B. The Si5317 operates at 3.3 V with an ac coupled differential PECL output and an ac coupled differential sine wave input from the RF generator at 0 dBm. Note that, as with any PLL, the output jitter that is below the loop BW is caused by the jitter at the input clock. The loop BW was 120 Hz.

7.1. Example: SONET OC-192

Figure 21. Typical Phase Noise Plot

Jitter Band	Jitter, RMS		
SONET OC48, 12 kHz to 20 MHz	250 fs		
SONET OC192_A, 20 kHz to 80 MHz	274 fs		
SONET OC192 B, 4 to 80 MHz	166 fs		
SONET OC192_C, 50 kHz to 80 MHz	267 fs		
Brick Wall, 800 Hz to 80 MHz	274 fs		

Note: SONET jitter bands include the SONET skirts. The phase noise plot is brick wall integration.

8. Typical Application Circuit

3. For schematic and layout examples, refer to Si5317-EVB User Manual.

Figure 22. Si5317 Typical Application Circuit

9. Pin Descriptions: Si5317

Note: Pin assignments are preliminary and subject to change.

Table 14. Si5317 Pin Descriptions

Table 14. Si5317 Pin Descriptions (Continued)

Table 14. Si5317 Pin Descriptions (Continued)

Pin # | Si5317 | Pull? 1 RST $|$ U 2 | FRQTBL | U, D 11 RATE0 U, D 15 RATE1 U, D 19 DEC D 20 INC D 22 BWSEL0 U, D 23 BWSEL1 U, D 24 | FRQSEL0 | U, D 25 FRQSEL1 U, D 26 FRQSEL2 U, D 27 | FRQSEL3 | U, D 30 SFOUT1 U, D 33 | SFOUT0 | U, D

Table 15. Si5317 Pull-Up/-Down

10. Ordering Guide

11. Package Outline: 36-Pin QFN

[Figure 23](#page-40-0) illustrates the package details for the Si5317. [Table 16](#page-40-1) lists the values for the dimensions shown in the illustration.

Figure 23. 36-Pin Quad Flat No-Lead (QFN)

Symbol	Millimeters			Symbol	Millimeters		
	Min	Nom	Max		Min	Nom	Max
A	0.80	0.85	0.90		0.50	0.60	0.70
A1	0.00	0.02	0.05	θ			12°
b	0.18	0.25	0.30	aaa			0.10
D	6.00 BSC			bbb			0.10
D ₂	3.95	4.10	4.25	CCC			0.08
e	0.50 BSC			ddd			0.10
E	6.00 BSC			eee			0.05
E2	3.95	4.10	4.25				

Table 16. Package Dimensions

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

3. This drawing conforms to JEDEC outline MO-220, variation VJJD.

4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

12. Recommended PCB Layout

Figure 24. PCB Land Pattern Diagram

Notes (General):

- **1.** All dimensions shown are in millimeters (mm) unless otherwise noted.
- **2.** Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
- **3.** This Land Pattern Design is based on IPC-SM-782 guidelines.

4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Notes (Solder Mask Design):

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μm minimum, all the way around the pad.

Notes (Stencil Design):

- **1.** A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- **2.** The stencil thickness should be 0.125 mm (5 mils).
- **3.** The ratio of stencil aperture to land pad size should be 1:1 for the perimeter pads.
- **4.** A 4 x 4 array of 0.80 mm square openings on 1.05 mm pitch should be used for the center ground pad.

Notes (Card Assembly):

- **1.** A No-Clean, Type-3 solder paste is recommended.
- **2.** The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

13. Si5317 Device Top Mark

DOCUMENT CHANGE LIST

Revision 0.1 to Revision 0.15

- Updated corresponding sections and pinouts to add CKOUT2, INC/DEC, and DBL2_BY functionality.
- Updated functional block diagram on page 1.
- Updated [Table 2](#page-3-3) IDD (DD is subscript).
- Added Differential Rise/Fall Time spec to [Table 2](#page-3-3).
- **Updated pin assignment symbol and pin description** on page 1 and in section [9](#page-35-0) to add CKOUT2, INC/DEC, and DBL2_BY.
- Added section [3.6. "PLL Bypass Mode"](#page-23-0).
- Updated section [8](#page-34-0) diagram to add CKOUT2 and DBL2_BY.
- Added additional CMOS Termination with attenuation figure.
- Corrected pin name assignment (pin28) diagram on page 1 and section [9](#page-35-0), page 35 to match pin description name.
- Updated all the frequency plans in [Table 8](#page-15-0) to provide coverage over the entire frequency range.

Revision 0.15 to Revision 0.2

- Updated bypass mode, ESD specifications and absolute max V_{DD} .
- Corrected INC/DEC pinout.

Revision 0.2 to Revision 1.0

- Removed Output Short to GNDon page 5.
- Removed duplicate lock time specification on page 11.
- Removed Time to Clear LOS alarm on page 11.
- Revised spurious noise values.
- Revised phase noise values.

Revision 1.0 to Revision 1.1

- Increased the maximum input/output frequency to 711 MHz
- Added reference to "AN591: Crystal Selection for the Si5315 and Si5317"

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